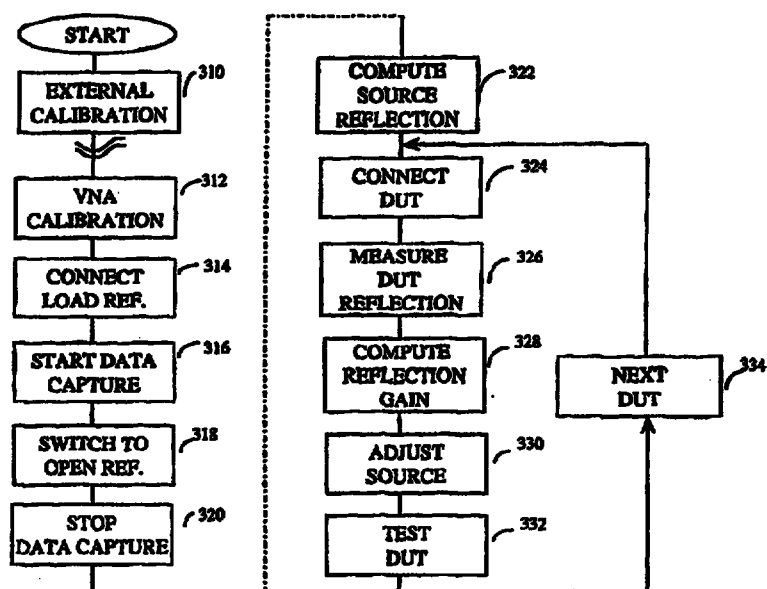


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|                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                  |           |                                                                                                                                                                                                              |
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| <b>(21) International Application Number:</b> PCT/US98/21541<br><b>(22) International Filing Date:</b> 13 October 1998 (13.10.98)<br><br><b>(30) Priority Data:</b><br>08/955,782      22 October 1997 (22.10.97)      US<br><br><b>(71) Applicant:</b> TERADYNE, INC. [US/US]; 321 Harrison Avenue, Boston, MA 02118 (US).<br><b>(72) Inventor:</b> BEGG, Matthew, Thomas; 29 Church Street #2, Waltham, MA 02154 (US).<br><b>(74) Agent:</b> GAMACHE, Richard, E.; Teradyne, Inc., 321 Harrison Avenue, Boston, MA 02118 (US). |           | <b>(81) Designated States:</b> CN, JP, KR, SG, European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE).<br><br><b>Published</b><br><i>With international search report.</i> |

**(54) Title:** AUTOMATED MICROWAVE TEST SYSTEM WITH IMPROVED ACCURACY**(57) Abstract**

An automatic test system for microwave components. The test system includes internally switchable calibration references. As part of a calibration routine, incident power from a source is measured. During the measurement, calibration references are switched to change the amount of power reflected back to the source. Changes in the incident power measured continuously while this change occurs. The resulting measurements allow the source match term to be determined. Correction is made to the source amplitude to adjust for the source match.